

<b>Notice of References Cited</b>	Application/Control No. 10/707,683	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner David A. Zarneke	Art Unit 2891	Page 1 of 1

U.S. PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0183946	10-2003	Fukuda et al.	257/778
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS						
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NON-PATENT DOCUMENTS		
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